L Number	Hits	Search Text	DB	Time stamp
1		(generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 11:39
-	3,03	test\$3 same (IC or integrated near	EPO; JPO;	2003,11,0. 11.03
1		circuit)	DERWENT;	
			IBM TDB	
2	1205	((generat\$3 or creat\$3 or build\$3) near3	USPĀT;	2003/11/07 13:49
		test\$3 same (IC or integrated near	EPO; JPO;	
		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 test\$3 and data	IBM_TDB	
3	367	(((generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 12:45
i		test\$3 same (IC or integrated near	EPO; JPO;	
		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 test\$3 and	IBM_TDB	
		data) and (first and second) near2 test\$3		0000/11/07 10:00
4	2	((((generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 12:02
		test\$3 same (IC or integrated near circuit)) and (determin\$3 or find\$3 or	EPO; JPO; DERWENT;	
	'	check\$3 or verify\$4) near4 test\$3 and	IBM TDB	
		data) and (first and second) near2 test\$3)	1511-100	
]		and (syntax near tree or AST)		
5	18	((((generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 12:02
	10	test\$3 same (IC or integrated near	EPO; JPO;	2000, 22, 0. 22102
		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 test\$3 and	IBM TDB	
		data) and (first and second) near2 test\$3)	_	
		and tree		
6	68	(((generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 12:48
	İ	test\$3 same (IC or integrated near	EPO; JPO;	
		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 test\$3 and	IBM_TDB	
		data) and (first and second) same test\$3		
	_	same success\$5		0000/11/07 10 40
7	5	(((generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 12:48
		test\$3 same (IC or integrated near	EPO; JPO;	
		circuit)) and (determin\$3 or find\$3 or	DERWENT; IBM TDB	•
		check\$3 or verify\$4) near4 test\$3 and data) and (first and second) same test\$3	IBM_IDB	
		same success\$5 and tree		
8	153		USPAT;	2003/11/07 13:50
1 "		test\$3 same (IC or integrated near	EPO; JPO;	
1		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 first same	IBM TDB	
		test\$3 and second near4 test	-	
9	0	(((generat\$3 or creat\$3 or build\$3) near3	USPAT;	2003/11/07 13:54
		test\$3 same (IC or integrated near	EPO; JPO;	
		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 first same	IBM_TDB	
	1	test\$3 and second near4 test) and		
1	1	(abstract near syntax near tree or syntax		
1.0	-	near tree)	USPAT;	2003/11/07 13:54
10	5	(((generat\$3 or creat\$3 or build\$3) near3 test\$3 same (IC or integrated near	EPO; JPO;	2003/11/0/ 13.34
		circuit)) and (determin\$3 or find\$3 or	DERWENT;	
		check\$3 or verify\$4) near4 first same	IBM TDB	
		test\$3 and second near4 test) and tree		
_	26	(717/\$.ccls. or 712/\$.ccls. or	USPAT;	2003/11/07 11:37
		714/\$.ccls.) and (insert\$3 or	EPO; JPO;	
		instrument\$6) same prefetch and (feedback	DERWENT;	
		or interact\$6)	IBM_TDB	
-	26	(717/\$.ccls. or 714/\$.ccls.) and (abstract	USPAT;	2002/10/23 14:12
		near syntax near tree or syntax near tree)	EPO; JPO;	
1		and (generat\$3 or build\$3 or design\$3 or	DERWENT;	
		develop\$3 or creat\$3) near3 test\$3	IBM_TDB	
-	15	(717/\$.ccls. or 714/\$.ccls.) and (abstract	USPAT;	2002/10/23 13:14
	1	near syntax near tree or syntax near tree)	EPO; JPO;	
		and (generat\$3 or build\$3 or design\$3 or	DERWENT;	
		develop\$3 or creat\$3) near3 test\$3 and	IBM_TDB	
	<u></u>	translat\$3 same execut\$3	<u></u>	L

=	5 (717/\$.ccls. or 714/\$.ccls.) and (abstract	USPAT;	2002/10/23 14:44
}	near syntax near tree or syntax near tree)	EPO; JPO;	
	and (generat\$3 or build\$3 or design\$3 or	DERWENT;	
	develop\$3 or creat\$3) near3 test\$3 and	IBM TDB	
	(abstract near syntax near tree or AST)	_	ŀ
	same (mutat\$3 or chang\$3 or reorganiz\$3)		[

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